


### GENERAL DESCRIPTION



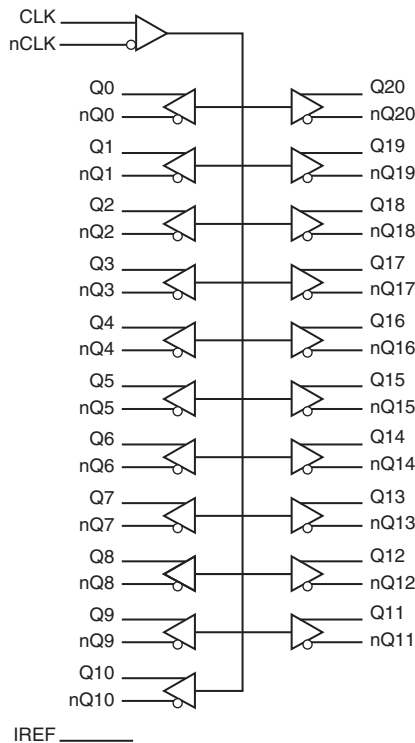
The ICS851021 is a 1-to-21 Differential Current Mode 0.7V HCSL Fanout Buffer. The ICS851021 is designed to translate any differential input signal levels to 0.7V differential current mode HCSL output levels. An external reference resistor is used to set the value of the current supplied to an external load/termination resistor. The load resistor value is chosen to equal the value of the characteristic line impedance of 50Ω. The ICS851021 is characterized at an operating supply voltage of 3.3V.

The 0.7V differential outputs, accurate crossover voltage and duty cycle makes the ICS851021 ideal for interfacing to PCI Express and FBDIMM applications.

### FEATURES

- Twenty-one 0.7V differential HCSL clock outputs
- Translates any differential input signal (LVPECL, LVHSTL, LVDS, 0.7V DIFF) to differential current mode HCSL levels without external bias networks
- Maximum output frequency: 250MHz
- Single or dual output drive
- Output skew: 395ps (maximum)
- Part-to-part skew: 335ps (maximum)
- Additive phase jitter, RMS: 0.20ps (typical)
- Output drift: 140ps (maximum)
- $V_{OH}$ : 850mV (maximum)
- 3.3V operating supply
- 0°C to 70°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

### BLOCK DIAGRAM



### PIN ASSIGNMENT

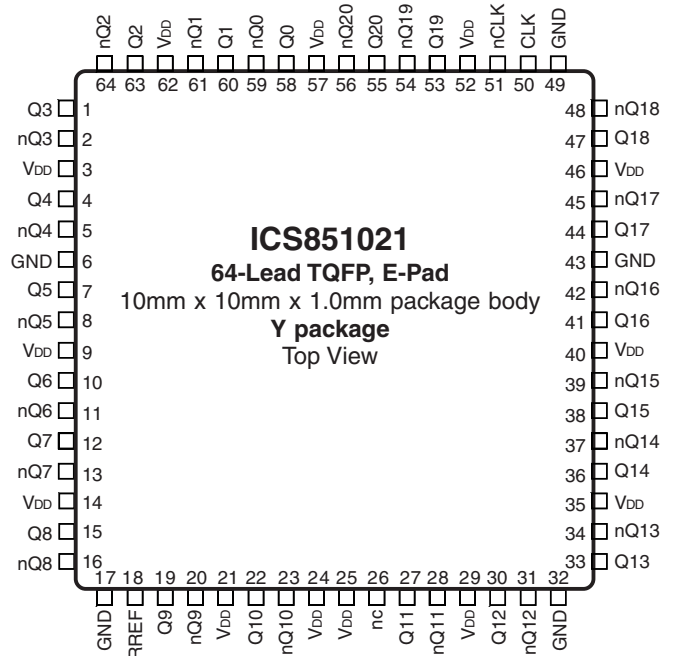


TABLE 1. PIN DESCRIPTIONS

Number	Name	Type	Description
1, 2	Q3, nQ3	Output	Differential output pair. HCSL interface levels.
3, 9, 14, 21, 24, 25, 29, 35, 40, 46, 52, 57, 62	V <sub>DD</sub>	Power	Core supply pins.
4, 5	Q4, nQ4	Output	Differential output pair. HCSL interface levels.
6, 17, 32, 43, 49	GND	Power	Power supply ground.
7, 8	Q5, nQ5	Output	Differential output pair. HCSL interface levels.
10, 11	Q6, nQ6	Output	Differential output pair. HCSL interface levels.
12, 13	Q7, nQ7	Output	Differential output pair. HCSL interface levels.
15, 16	Q8, nQ8	Output	Differential output pair. HCSL interface levels.
18	IREF	Input	External fixed precision resistor (475Ω) from this pin to ground provides a reference current used for differential current-mode Qx/nQx clock outputs.
19, 20	Q9, nQ9	Output	Differential output pair. HCSL interface levels.
22, 23	Q10, nQ10	Output	Differential output pair. HCSL interface levels.
26	nc	Unused	No connect.
27, 28	Q11, nQ11	Output	Differential output pair. HCSL interface levels.
30, 31	Q12, nQ12	Output	Differential output pair. HCSL interface levels.
33, 34	Q13, nQ13	Output	Differential output pair. HCSL interface levels.
36, 37	Q14, nQ14	Output	Differential output pair. HCSL interface levels.
38, 39	Q15, nQ15	Output	Differential output pair. HCSL interface levels.
41, 42	Q16, nQ16	Output	Differential output pair. HCSL interface levels.
44, 45	Q17, nQ17	Output	Differential output pair. HCSL interface levels.
47, 48	Q18, nQ18	Output	Differential output pair. HCSL interface levels.
50	CLK	Input	Non inverting differential clock input.
51	nCLK	Input	Inverting differential clock input.
53, 54	Q19, nQ19	Output	Differential output pair. HCSL interface levels.
55, 56	Q20, nQ20	Output	Differential output pair. HCSL interface levels.
58, 59	Q0, nQ0	Output	Differential output pair. HCSL interface levels.
60, 61	Q1, nQ1	Output	Differential output pair. HCSL interface levels.
64, 63	Q2, nQ2	Output	Differential output pair. HCSL interface levels.

## OUTPUT DRIVER CURRENT

The ICS851021 outputs are HCSL differential current drive with the current being set with a resistor from I<sub>REF</sub> to ground. For a *single load* and a 50Ω p.c. board trace, the drive current would typically be set with a R<sub>REF</sub> of 950Ω which produces an I<sub>REF</sub> of 2.32mA. The I<sub>REF</sub> is multiplied by a current mirror to an output drive of 6\*2.32mA or 13.92mA. See *Figure 1* for current mirror and output drive details.

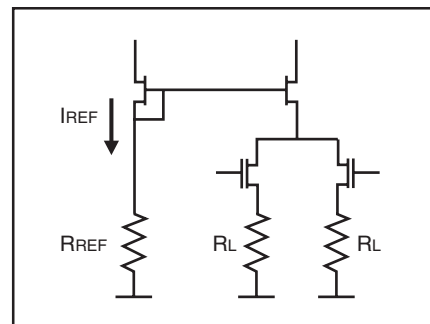


FIGURE 1. HCSL CURRENT MIRROR AND OUTPUT DRIVE

**ABSOLUTE MAXIMUM RATINGS**

Supply Voltage, $V_{DD}$	4.6V
Inputs, $V_I$	-0.5V to $V_{DD} + 0.5$ V
Outputs, $V_O$	-0.5V to $V_{DD} + 0.5$ V
Package Thermal Impedance, $\theta_{JA}$	31.8°C/W (0 mps)
Storage Temperature, $T_{STG}$	-65°C to 150°C

NOTE: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

**TABLE 2A. POWER SUPPLY DC CHARACTERISTICS,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = 0^\circ\text{C}$  TO  $70^\circ\text{C}$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Positive Supply Voltage		3.135	3.3	3.465	V
$I_{DD}$	Power Supply Current				105	mA

**TABLE 2B. DIFFERENTIAL DC CHARACTERISTICS,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = 0^\circ\text{C}$  TO  $70^\circ\text{C}$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$I_{IH}$	Input High Current	CLK, nCLK $V_{DD} = V_{IN} = 3.465\text{V}$			5	$\mu\text{A}$
$I_{IL}$	Input Low Current	CLK, nCLK $V_{DD} = 3.465\text{V}, V_{IN} = 0\text{V}$			5	$\mu\text{A}$
$V_{PP}$	Peak-to-Peak Input Voltage		0.15		1.3	V
$V_{CMR}$	Common Mode Input Voltage; NOTE 1		GND + 0.5		$V_{DD} - 0.85$	V

NOTE 1: Common mode voltage is defined as  $V_{IH}$ .

**TABLE 3. AC CHARACTERISTICS,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = 0^\circ C$  TO  $70^\circ C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$f_{MAX}$	Output Frequency				250	MHz
$t_{PD}$	Propagation Delay; NOTE 1	Measured on at VOX	1.5		2.75	ns
$t_{jit}$	Buffer Additive Phase Jitter, RMS; Refer to Additive Phase Jitter Section	CLK = 200MHz, (Integration Range: 12kHz – 30MHz)		0.20		ps
$t_{sk(o)}$	Output Skew; NOTE 2, 3	Measured on at VOX			395	ps
$t_{sk(pp)}$	Part-to-Part Skew; NOTE 3, 4				335	ps
$t_{sk(drift)}$	Output Drift; NOTE 5				140	ps
$V_{MAX}$	Voltage High; NOTE 6	$f \leq 150MHz$	500		850	mV
$V_{MIN}$	Voltage Low; NOTE 6	$f \leq 150MHz$	-150		150	mV
$V_{CROSS}$	Absolute Crossing Voltage		250		550	mV
$\Delta V_{CROSS}$	Total Variation of $V_{CROSS}$ over all edges				140	mV
	Rise/Fall Edge Rate: NOTE 7, 8		0.6		4.0	V/ns
$\Delta t_R / \Delta t_F$	Rise/Fall Time Matching; NOTE 9				20	%
odc	Output Duty Cycle; NOTE 10		47		53	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE: Current adjust set for  $V_{OH} = 0.7V$ . Measurements refer to PCIEX outputs only.

NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at the output differential cross points.

NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 4: Defined as the skew between outputs on different devices operating at the same supply voltage, same temperature and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at the differential cross points.

NOTE 5: Output Drift is measured as the change in the time placement of the differential crosspoint for each output on a given device due to a change in temperature and supply voltage. Measured at the differential cross points.

NOTE 6: Measurement using  $R_{REF} = 950\Omega$ ,  $R_{LOAD} = 50\Omega$ .

NOTE 7: Measurement taken from differential waveform.

NOTE 8: Measured from -150mV to +150mV on the differential waveform (derived from CLK minus nCLK). The signal must be monotonic through the measurement region for rise and fall time. The 300mV measurement window is centered on the differential zero crossing.

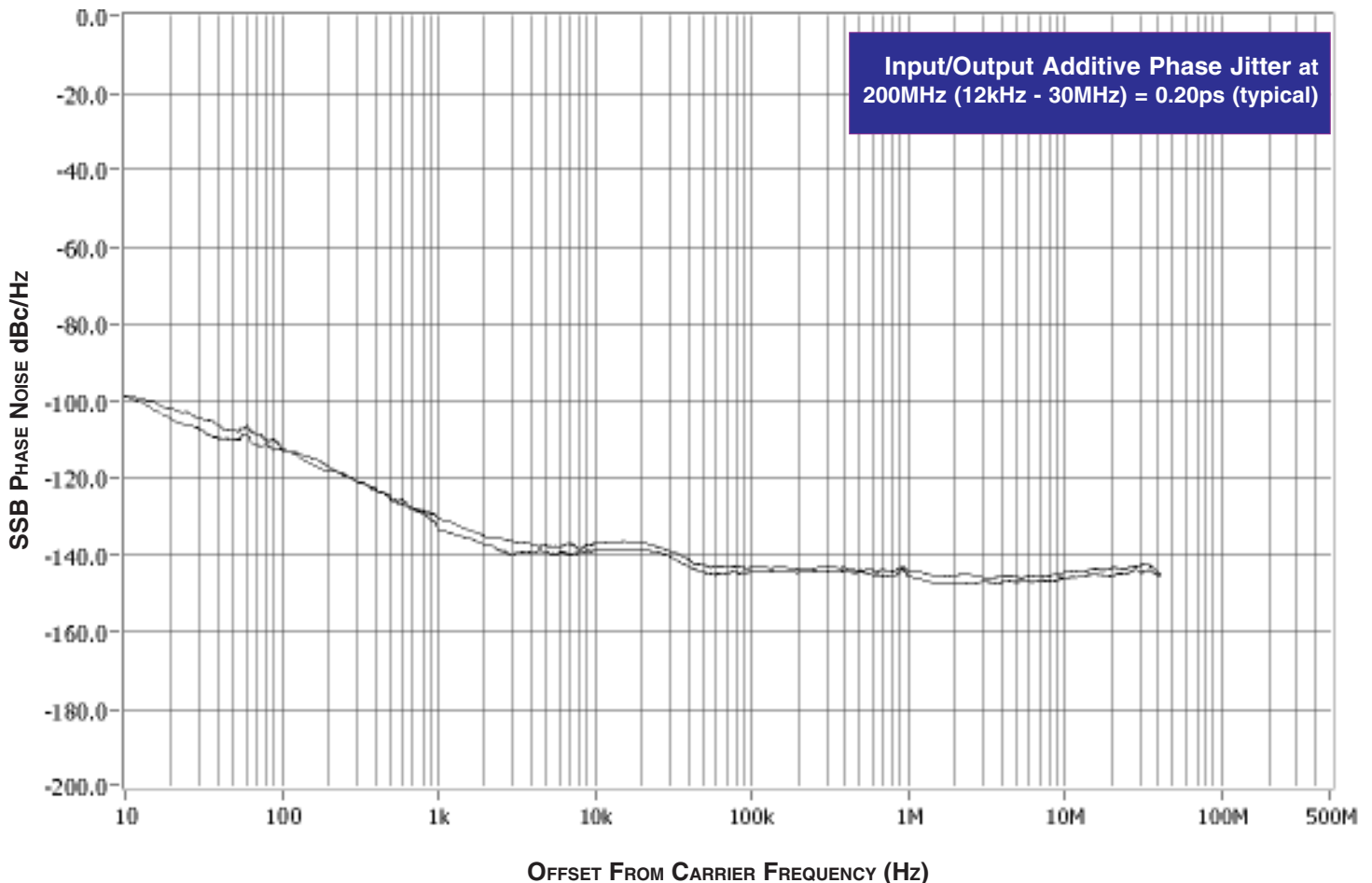
NOTE 9: Matching applies to rising edge rate for Qx and falling edge rate for nQx. It is measured using a  $\pm 75mV$  window centered on the median cross point where Qx rising meets nQx falling.

NOTE 10: Assuming 50% input duty cycle. Data taken at  $f \leq 200MHz$ , unless otherwise specified.

## ADDITIVE PHASE JITTER

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the ***dBc Phase Noise***. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz

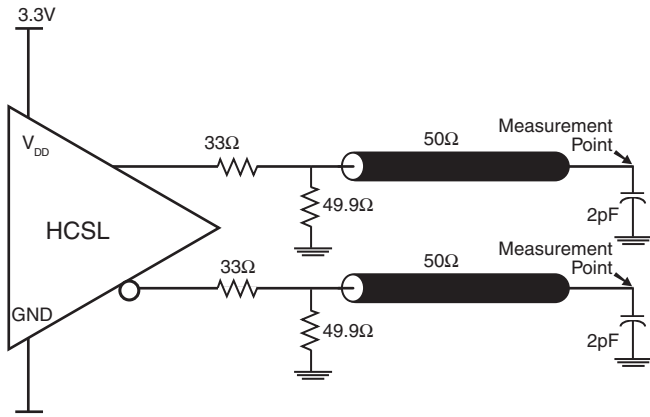
band to the power in the fundamental. When the required offset is specified, the phase noise is called a ***dBc*** value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



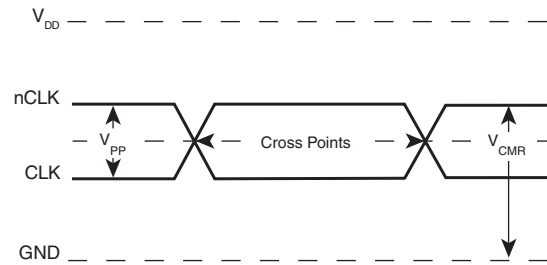
As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the

device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

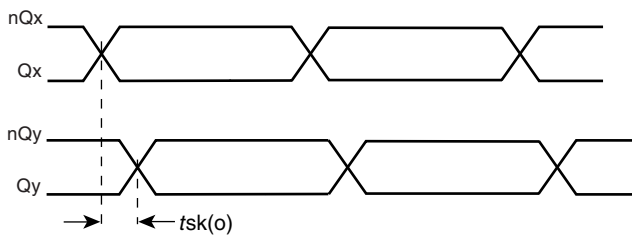
# PARAMETER MEASUREMENT INFORMATION



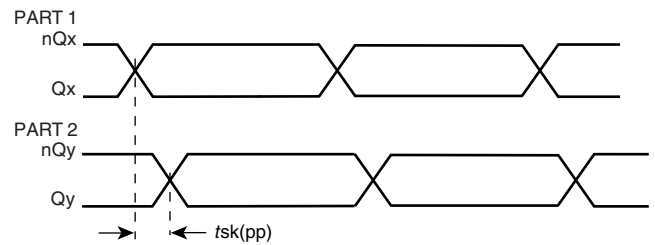
**3.3V OUTPUT LOAD AC TEST CIRCUIT**



**DIFFERENTIAL INPUT LEVEL**



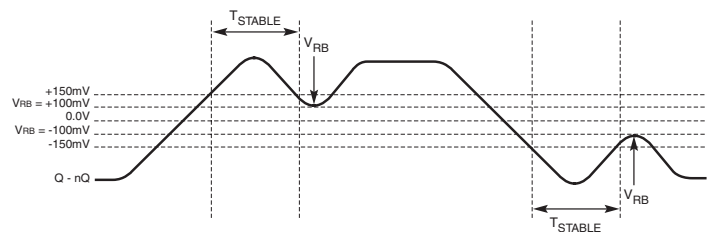
**OUTPUT SKEW**



**PART-TO-PART SKEW**

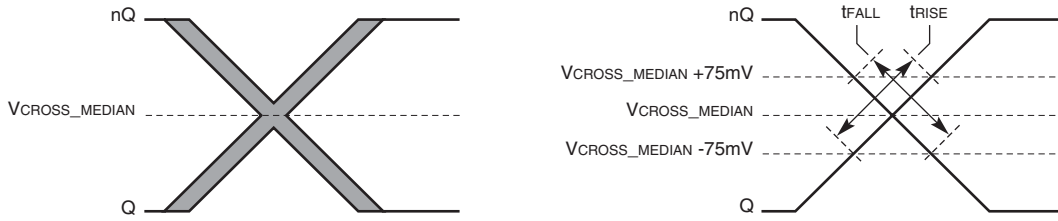


**DIFFERENTIAL MEASUREMENT POINTS FOR RISE/FALL TIME**

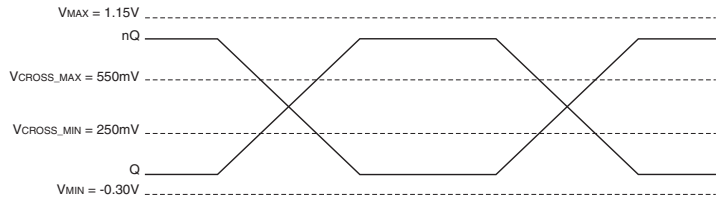
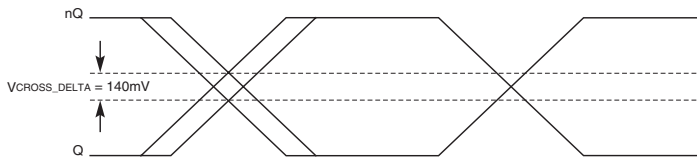


**DIFFERENTIAL MEASUREMENT POINTS FOR RINGBACK**

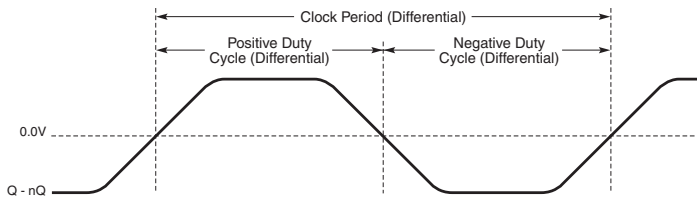
# PARAMETER MEASUREMENT INFORMATION, CONTINUED



## SE MEASUREMENT POINTS FOR RISE/FALL TIME MATCHING



## SE MEASUREMENT POINTS FOR DELTA CROSS POINT



## SE MEASUREMENT POINTS FOR ABSOLUTE CROSS POINT/SWING

## DIFFERENTIAL MEASUREMENT POINTS FOR DUTY CYCLE PERIOD

## APPLICATION INFORMATION

### WIRING THE DIFFERENTIAL INPUT TO ACCEPT SINGLE ENDED LEVELS

Figure 2 shows how a differential input can be wired to accept single ended levels. The reference voltage  $V_{REF} = V_{DD}/2$  is generated by the bias resistors R1 and R2. The bypass capacitor (C1) is used to help filter noise on the DC bias. This bias circuit should be located as close to the input pin as possible. The ratio of R1 and R2 might need to be adjusted to position the  $V_{REF}$  in the center of the input voltage swing. For example, if the input clock swing is 2.5V and  $V_{DD} = 3.3V$ , R1 and R2 value should be adjusted to set  $V_{REF}$  at 1.25V. The values below are for when both the single-ended swing and  $V_{DD}$  are at the same voltage. This configuration requires that the sum of the output impedance of the driver ( $R_o$ ) and the series resistance ( $R_s$ ) equals the transmission line impedance. In addition, matched termination at the input will attenuate the signal in half. This can be done in one of two ways. First, R3 and R4 in parallel should equal the transmission line

impedance. For most 50 applications, R3 and R4 can be 100Ω. The values of the resistors can be increased to reduce the loading for slower and weaker LVCMOS driver. When using single ended signaling, the noise rejection benefits of differential signaling are reduced. Even though the differential input can handle full rail LVCMOS signaling, it is recommended that the amplitude be reduced. The datasheet specifies a lower differential amplitude, however this only applies to differential signals. For single-ended applications, the swing can be larger, however  $V_{IL}$  cannot be less than  $-0.3V$  and  $V_{IH}$  cannot be more than  $V_{DD} + 0.3V$ . Though some of the recommended components might not be used, the pads should be placed in the layout. They can be utilized for debugging purposes. The datasheet specifications are characterized and guaranteed by using a differential signal.

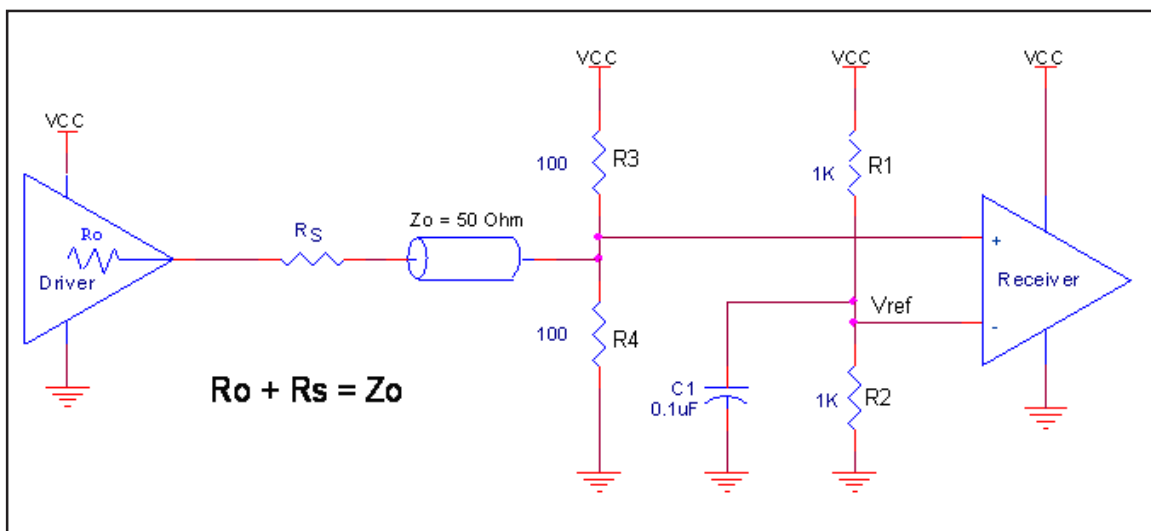


FIGURE 2. SINGLE ENDED SIGNAL DRIVING DIFFERENTIAL INPUT

### RECOMMENDATIONS FOR UNUSED OUTPUT PINS

#### OUTPUTS:

##### DIFFERENTIAL OUTPUTS

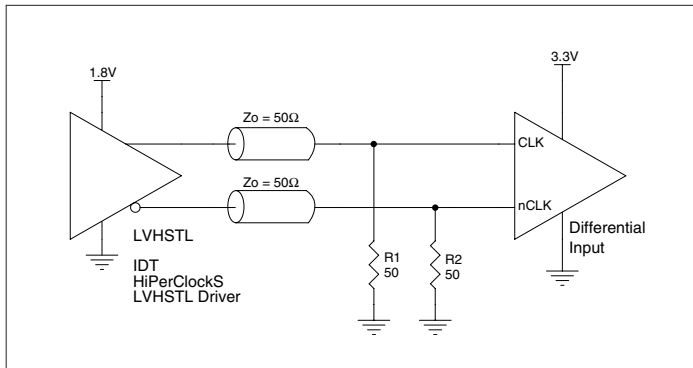
All unused differential outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.



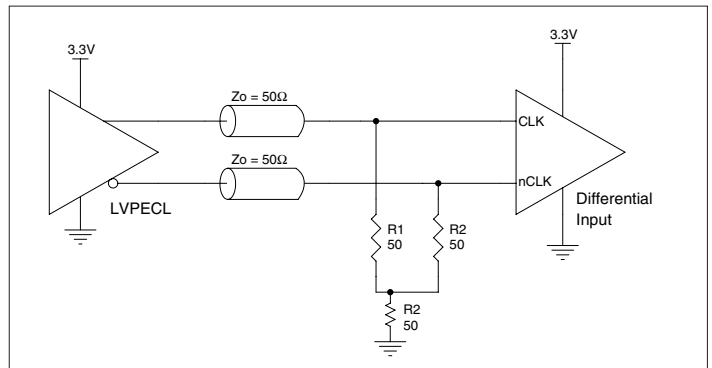
### DIFFERENTIAL CLOCK INPUT INTERFACE

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, HCSL and other differential signals. Both differential signals must meet the  $V_{PP}$  and  $V_{CMR}$  input requirements. Figures 3A to 3E show interface examples for the CLK/nCLK input driven by the most common driver types. The input interfaces suggested here are examples

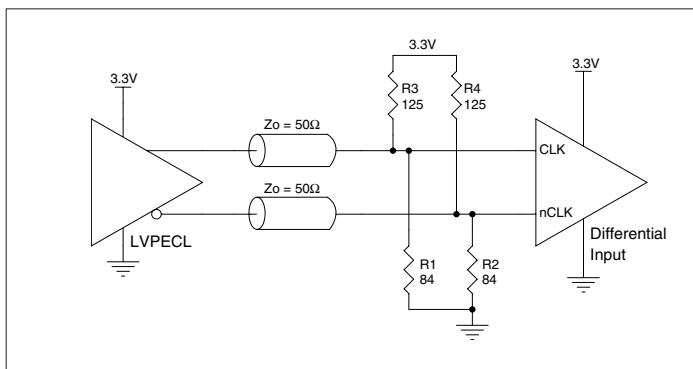
only. Please consult with the vendor of the driver component to confirm the driver termination requirements. For example in Figure 3A, the input termination applies for IDT open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.



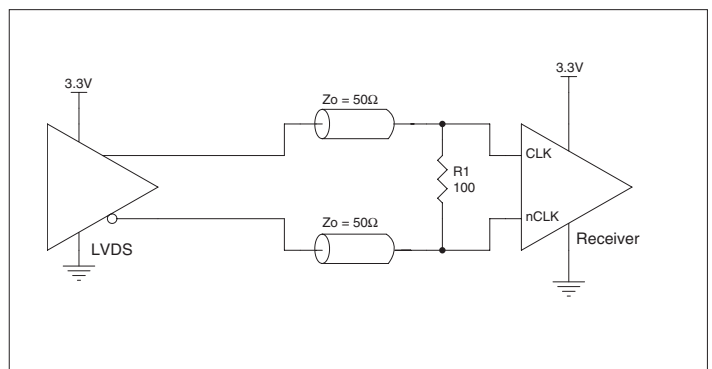
**FIGURE 3A. CLK/nCLK INPUT DRIVEN BY AN IDT OPEN EMITTER LVHSTL DRIVER**



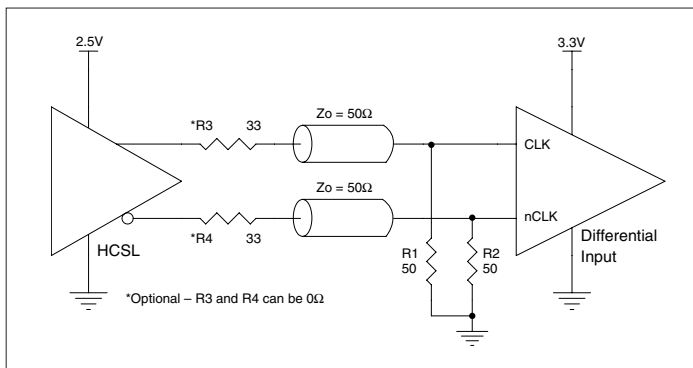
**FIGURE 3B. CLK/nCLK INPUT DRIVEN BY A 3.3V LVPECL DRIVER**



**FIGURE 3C. CLK/nCLK INPUT DRIVEN BY A 3.3V LVPECL DRIVER**



**FIGURE 3D. CLK/nCLK INPUT DRIVEN BY A 3.3V LVDS DRIVER**



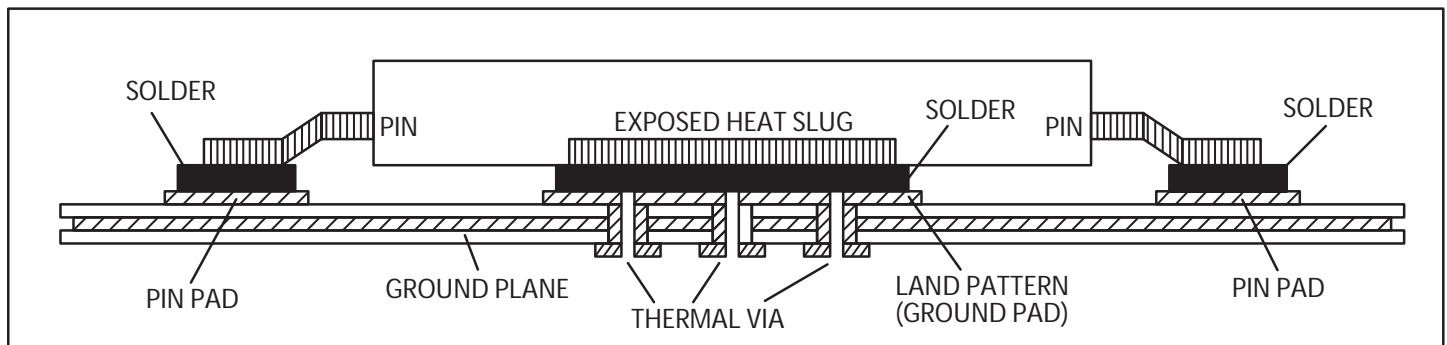
**FIGURE 3E. CLK/nCLK INPUT DRIVEN BY A 3.3V HCSL DRIVER**

## EPAD THERMAL RELEASE PATH

In order to maximize both the removal of heat from the package and the electrical performance, a land pattern must be incorporated on the Printed Circuit Board (PCB) within the footprint of the package corresponding to the exposed metal pad or exposed heat slug on the package, as shown in *Figure 4*. The solderable area on the PCB, as defined by the solder mask, should be at least the same size/shape as the exposed pad/slug area on the package to maximize the thermal/electrical performance. Sufficient clearance should be designed on the PCB between the outer edges of the land pattern and the inner edges of pad pattern for the leads to avoid any shorts.

While the land pattern on the PCB provides a means of heat transfer and electrical grounding from the package to the board through a solder joint, thermal vias are necessary to effectively conduct from the surface of the PCB to the ground plane(s). The land pattern must be connected to ground through these vias. The vias act as “heat pipes”. The number of vias (i.e. “heat pipes”)

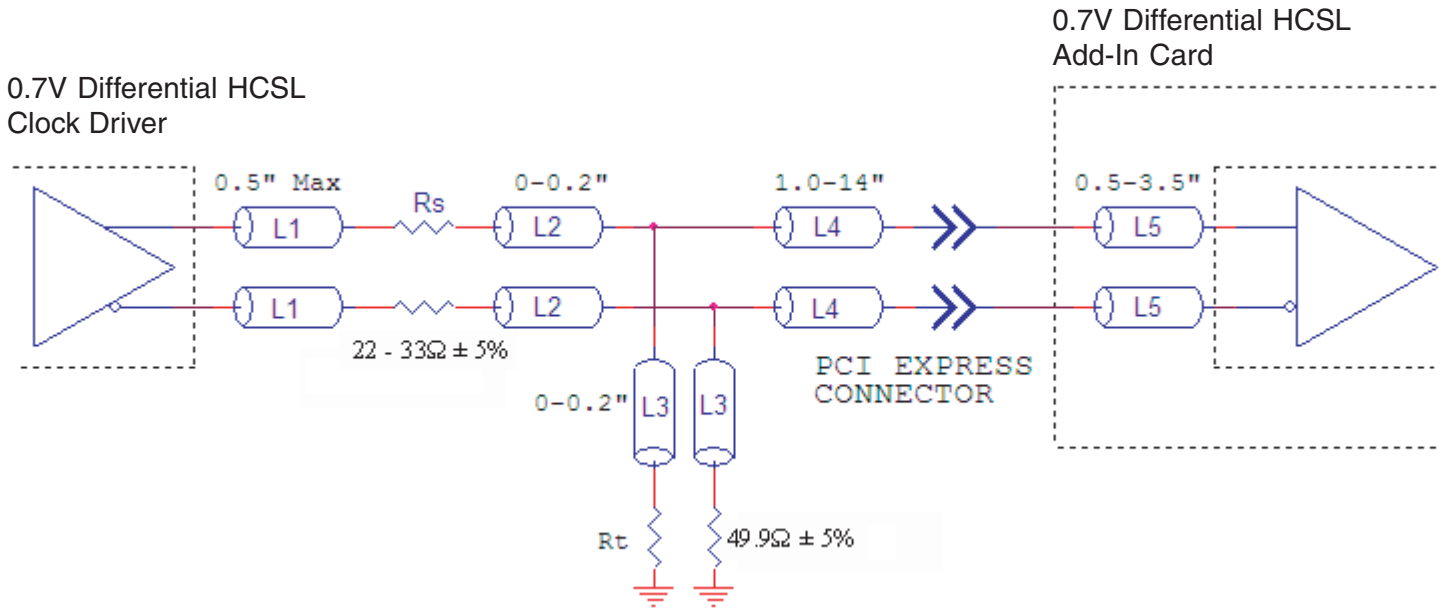
are application specific and dependent upon the package power dissipation as well as electrical conductivity requirements. Thus, thermal and electrical analysis and/or testing are recommended to determine the minimum number needed. Maximum thermal and electrical performance is achieved when an array of vias is incorporated in the land pattern. It is recommended to use as many vias connected to ground as possible. It is also recommended that the via diameter should be 12 to 13mils (0.30 to 0.33mm) with 1oz copper via barrel plating. This is desirable to avoid any solder wicking inside the via during the soldering process which may result in voids in solder between the exposed pad/slug and the thermal land. Precautions should be taken to eliminate any solder voids between the exposed heat slug and the land pattern. Note: These recommendations are to be used as a guideline only. For further information, refer to the Application Note on the *Surface Mount Assembly* of Amkor’s Thermally/Electrically Enhance Leadframe Base Package, Amkor Technology.



**FIGURE 4. ASSEMBLY FOR EXPOSED PAD THERMAL RELEASE PATH –SIDE VIEW (DRAWING NOT TO SCALE)**

**RECOMMENDED TERMINATION**

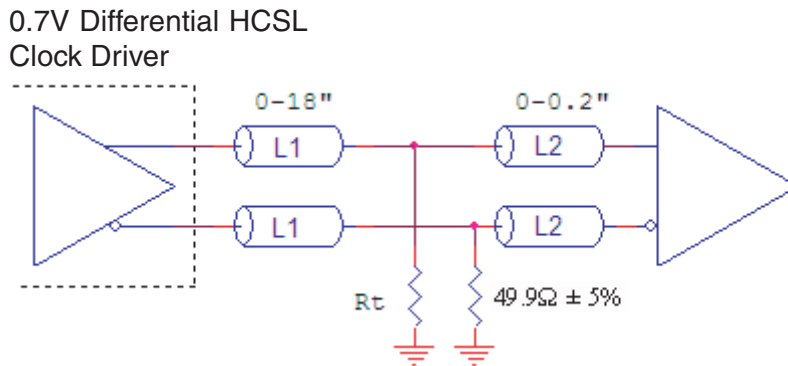
Figure 5A is the recommended termination for applications which require the receiver and driver to be on a separate PCB. All traces should be 50Ω impedance.



**FIGURE 5A. RECOMMENDED TERMINATION**

Figure 5B is the recommended termination for applications which require a point to point connection and contain the driver

and receiver on the same PCB. All traces should all be 50Ω impedance.



**FIGURE 5B. RECOMMENDED TERMINATION**

## POWER CONSIDERATIONS

This section provides information on power dissipation and junction temperature for the ICS851021. Equations and example calculations are also provided.

### 1. Power Dissipation.

The total power dissipation for the ICS851021 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

**NOTE:** Please refer to Section 3 for details on calculating power dissipated in the load.

- Power (core)<sub>MAX</sub> =  $V_{DD,MAX} * I_{DD,MAX} = 3.465V * 105mA = 363.83mW$
- Power (outputs)<sub>MAX</sub> = **47.3mW/Loaded Output pair**  
If all outputs are loaded, the total power is  $21 * 47.3mW = 993.3mW$

$$\text{Total Power}_{MAX} (3.465V, \text{ with all outputs switching}) = 363.83mW + 993.3mW = 1357.13mW$$

### 2. Junction Temperature.

Junction temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature,  $T_j$ , to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for  $T_j$  is as follows:  $T_j = \theta_{JA} * Pd_{total} + T_A$

$T_j$  = Junction Temperature

$\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

$Pd_{total}$  = Total Device Power Dissipation (example calculation is in Section 1 above)

$T_A$  = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 31.8°C/W per Table 4 below.

Therefore,  $T_j$  for an ambient temperature of 70°C with all outputs switching is:

$$70^\circ\text{C} + 1.357\text{W} * 31.8^\circ\text{C/W} = 113.2^\circ\text{C}. \text{ This is below the limit of } 125^\circ\text{C}.$$

This calculation is only an example.  $T_j$  will obviously vary depending on the number of loaded outputs, supply voltage, air flow, and the type of board (single layer or multi-layer).

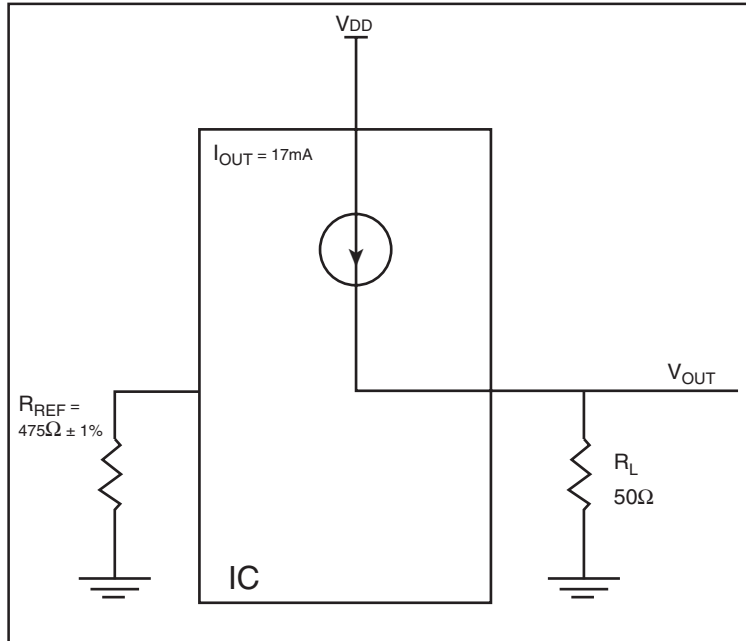
**TABLE 4. THERMAL RESISTANCE  $\theta_{JA}$  FOR 64-PIN TQFP, FORCED CONVECTION**

$\theta_{JA}$ by Velocity (Meters per Second)			
	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	31.8°C/W	25.8°C/W	24.2°C/W

### 3. Calculations and Equations.

The purpose of this section is to calculate power dissipation on the IC per HCSL output pair.

HCSL output driver circuit and termination are shown in *Figure 6*.



**FIGURE 6. HCSL DRIVER CIRCUIT AND TERMINATION**

HCSL is a current steering output which sources a maximum of 17mA of current per output. To calculate worst case on-chip power dissipation, use the following equations which assume a 50Ω load to ground.

The highest power dissipation occurs when  $V_{DD}$  is HIGH.

$$\begin{aligned} \text{Power} &= (V_{DD\_HIGH} - V_{OUT}) * I_{OUT}, \text{ since } V_{OUT} = I_{OUT} * R_L \\ &= (V_{DD\_HIGH} - I_{OUT} * R_L) * I_{OUT} \\ &= (3.63V - 17mA * 50\Omega) * 17mA \end{aligned}$$

Total Power Dissipation per output pair = **47.3mW**

## RELIABILITY INFORMATION

**TABLE 5.  $\theta_{JA}$  vs. AIR FLOW TABLE FOR 64 LEAD TQFP, E-PAD**

$\theta_{JA}$ by Velocity (Meters Per Second)			
	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	31.8°C/W	25.8°C/W	24.2°C/W

### TRANSISTOR COUNT

The transistor count for ICS851021 is: 843

PACKAGE OUTLINE - Y SUFFIX FOR 64 LEAD TQFP, E-PAD

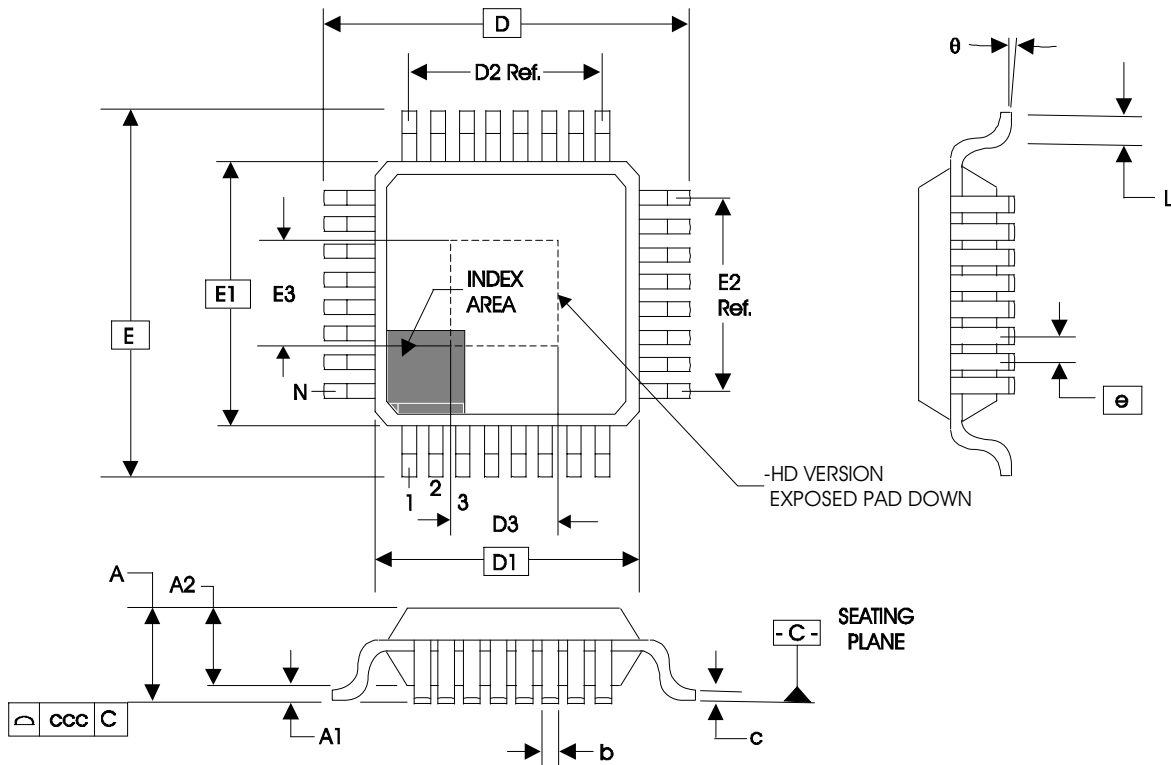


TABLE 6. PACKAGE DIMENSIONS

JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS			
SYMBOL	ACD-HD		
	MINIMUM	NOMINAL	MAXIMUM
N	64		
A	--	--	1.20
A1	0.05	0.10	0.15
A2	0.95	1.0	1.05
b	0.17	0.22	0.27
c	0.09	--	0.20
D	12.00 BASIC		
D1	10.00 BASIC		
D2	7.50 Ref.		
E	12.00 BASIC		
E1	10.00 BASIC		
E2	7.50 Ref.		
e	0.50 BASIC		
L	0.45	0.60	0.75
θ	0°	--	7°
ccc	--	--	0.08
D3 & E3	4.5	--	5.5

Reference Document: JEDEC Publication 95, MS-026

**TABLE 7. ORDERING INFORMATION**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
851021AY	ICS851021AY	64 lead TQFP, E-Pad	tray	0°C to 70°C
851021AYT	ICS851021AY	64 lead TQFP, E-Pad	500 tape & reel	0°C to 70°C
851021AYLFF	ICS851021AYLFF	64 Lead "Lead-Free" TQFP, E-Pad	tray	0°C to 70°C
851021AYLFT	ICS851021AYLFF	64 Lead "Lead-Free" TQFP, E-Pad	500 tape & reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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REVISION HISTORY SHEET				
Rev	Table	Page	Description of Change	Date
B	T1	1	Pin Assignment, corrected pin 25 from $V_{DDA}$ to $V_{DD}$ .	5/25/08
		2	Pin Description Table - deleted $V_{DDA}$ (pin #25) row, and added pin #25 to $V_{DD}$ row.	
		12	Power Considerations - corrected total power calculation and $T_j$ calculation.	
B	T3	4	AC Characteristics Table - added Thermal note.	3/3/10
		8	Updated Wiring the Differential Input to Accept Single Ended Levels.	
	9	Updated Differential Clock Input Interface.		
	T6	15	Package Dimensions - corrected D3 & E3 dimensions.	
		Updated datasheet's Head/Footer.		



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